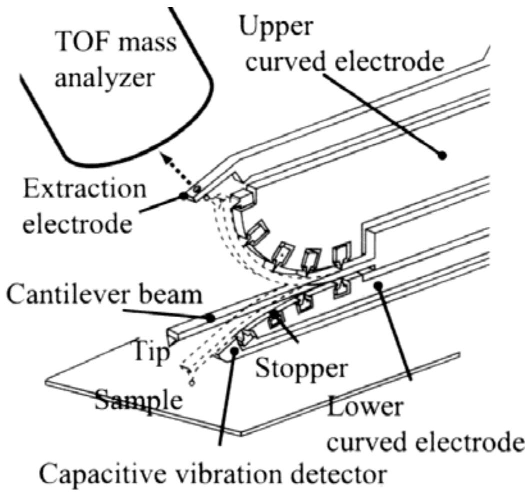
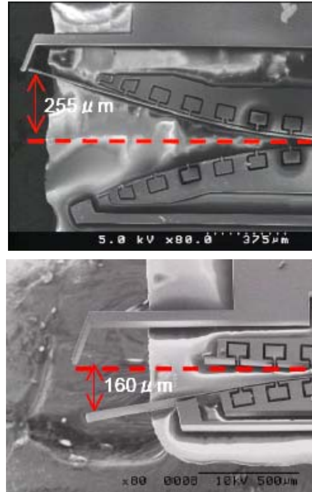
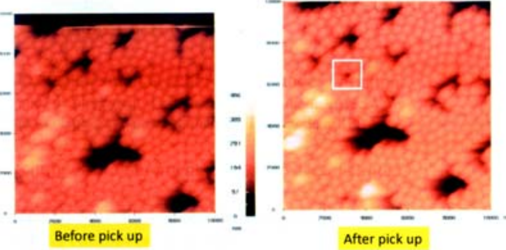
C10

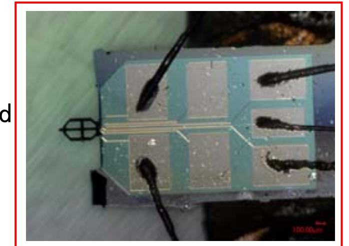
走査プローブ顕微鏡(SPM)プローブ







静電駆動飛行時間質量分析機能付 AFM プローブ



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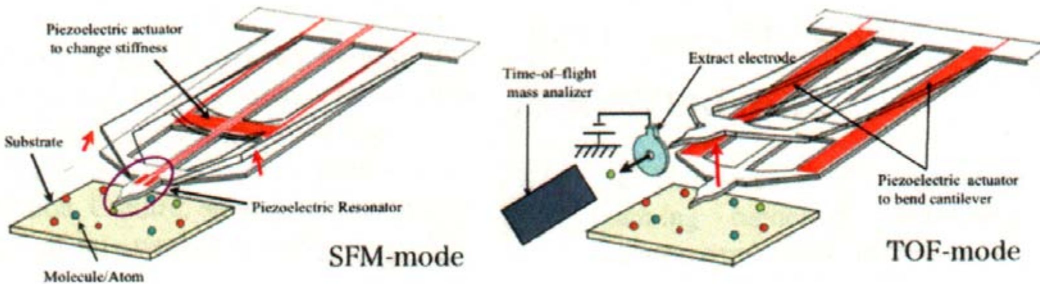

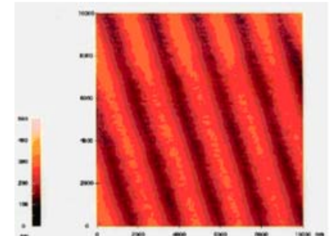

圧電駆動飛行時間質量分析機能付 AFM プローブ

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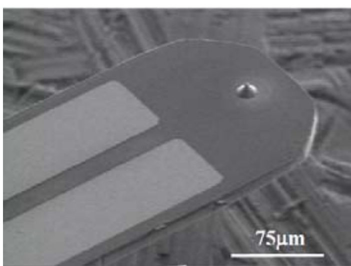

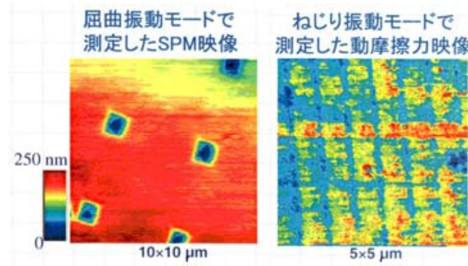

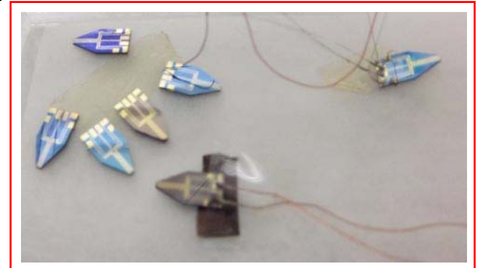

水晶 AFM プローブ

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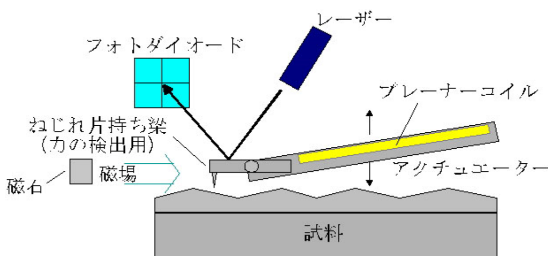

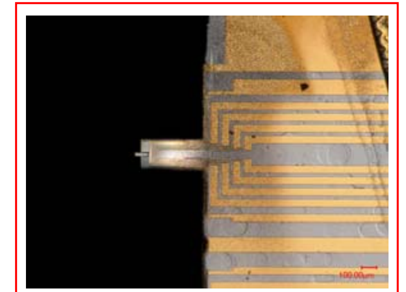

電磁式 AFM プローブ

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